

# **Electron sources at ATF/LUCX facility of KEK Part-II**

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Inter University Accelerator Centre, New Delhi**

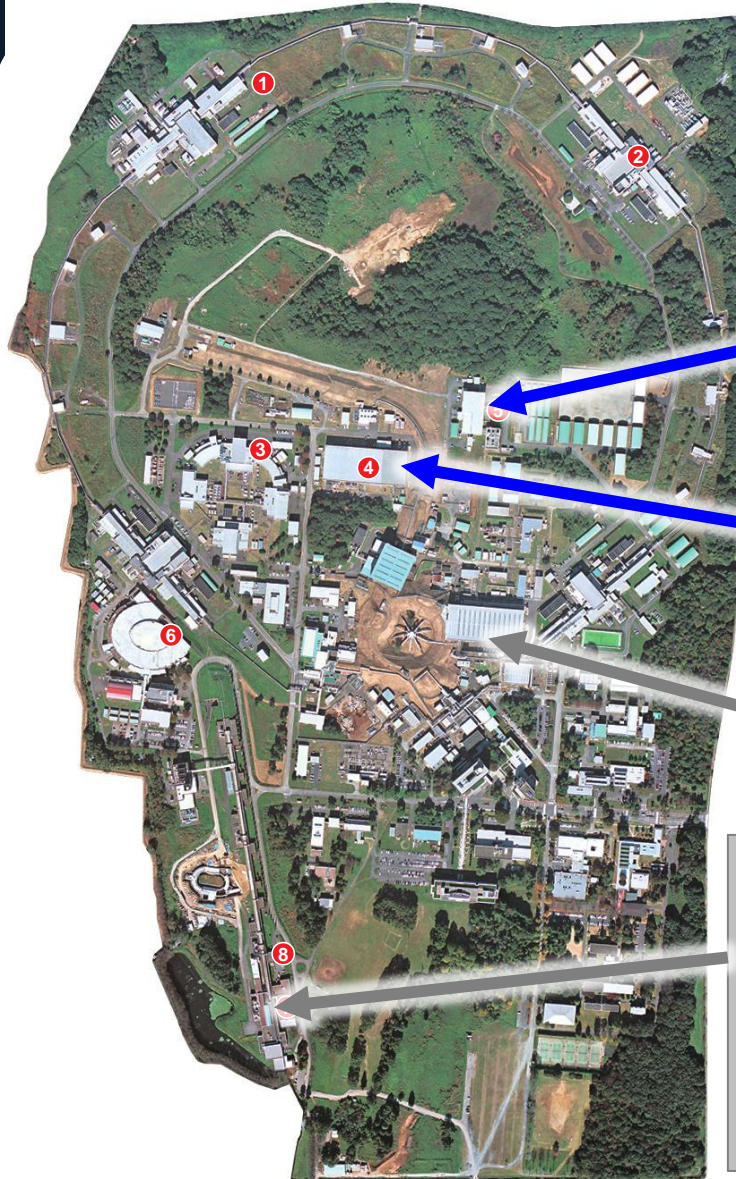
**16 February 2015**

# Part-II

focused on experiences of  $\text{Cs}_2\text{Te}$   
photocathode at KEK

- preparation and transport
- experiences with the RF gun

# Electron sources of the KEK Accelerators



## Cs<sub>2</sub>Te photocathode RF gun

- well established
- compact and longer lifetime

STF

L-band 1.3 GHz

ATF/LUCX

S-band 2.8 GHz

cERL (500kV DC gun for CW)  
GaAs photocathode

KEKB

Thermionic Gun

SuperKEKB

Quasi traveling wave side coupled cavity gun  
advanced, under development

# Electron source of ATF

## RF gun: S-band 3.6 cell

Typical operation for ATF

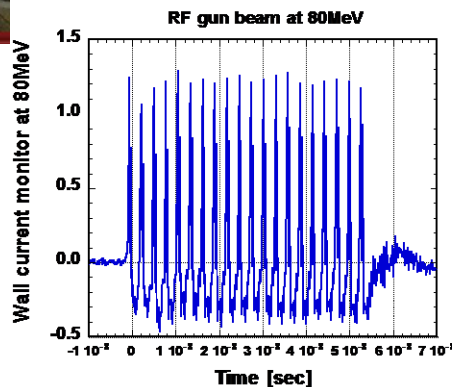
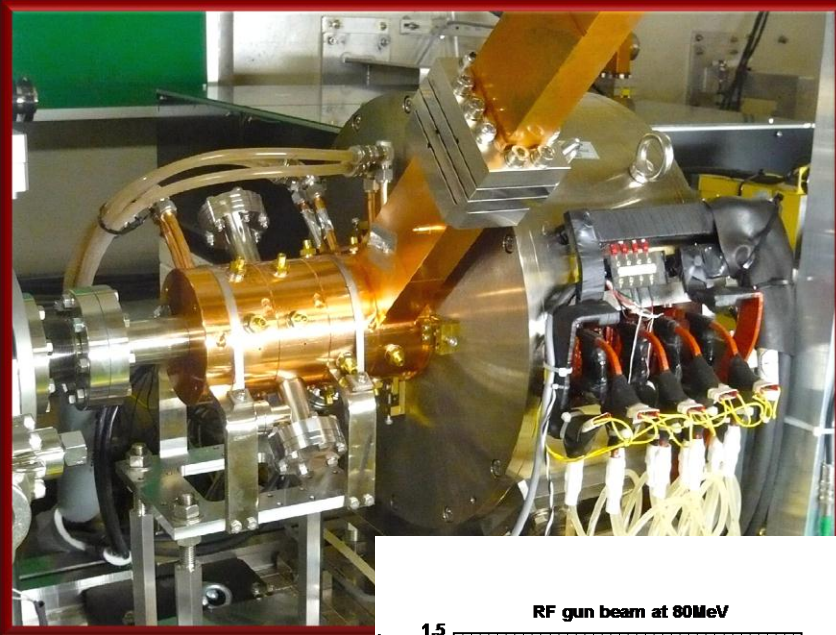
- **5 MeV** (limited by available RF power)
- 1~20 bunch/pulse (2.8 ns spacing)
- **$1 \times 10^{10}$  electrons/bunch**
- 3 Hz repetition

## Laser

- Nd:YAG: 266 nm
- 357 MHz
- 1 uJ/bunch
- 1~20 bunch by pockels cell

## Cathode

- **Cs<sub>2</sub>Te: QE ~1%**



Cs<sub>2</sub>Te  
Photocathode  
RF Gun



1.3 GeV S-band Electron LINAC (~70m)

# Present merits of Cs<sub>2</sub>Te photocathode

Photocathode	QE	
Pure Metals (Cu, Mg,...)	10 <sup>-5</sup> ~ 10 <sup>-4</sup>	<ul style="list-style-type: none"> <li>• UV laser</li> <li>• can handle in air</li> <li>• back bombardment</li> </ul>
<b>Cs<sub>2</sub>Te</b>	<b>10<sup>-2</sup> ~ 10<sup>-1</sup></b>	<ul style="list-style-type: none"> <li>• UHV is required, Oxidation</li> <li>• UV laser is required</li> <li>• longer lifetime</li> <li>• well established</li> </ul>
Multi-Alkaline CsKSb,...	10 <sup>-2</sup>	R&D phase <b>attractive green laser response</b>
Others,...	...	...

**Higher intensity e- beam generation by a reasonable laser power**

example for ATF:

$$2 \times 10^{10} \text{ e}^-/\text{bunch} = 1 \% (\text{QE}) \times 2 \text{ } \mu\text{J}/\text{laser-pulse}$$

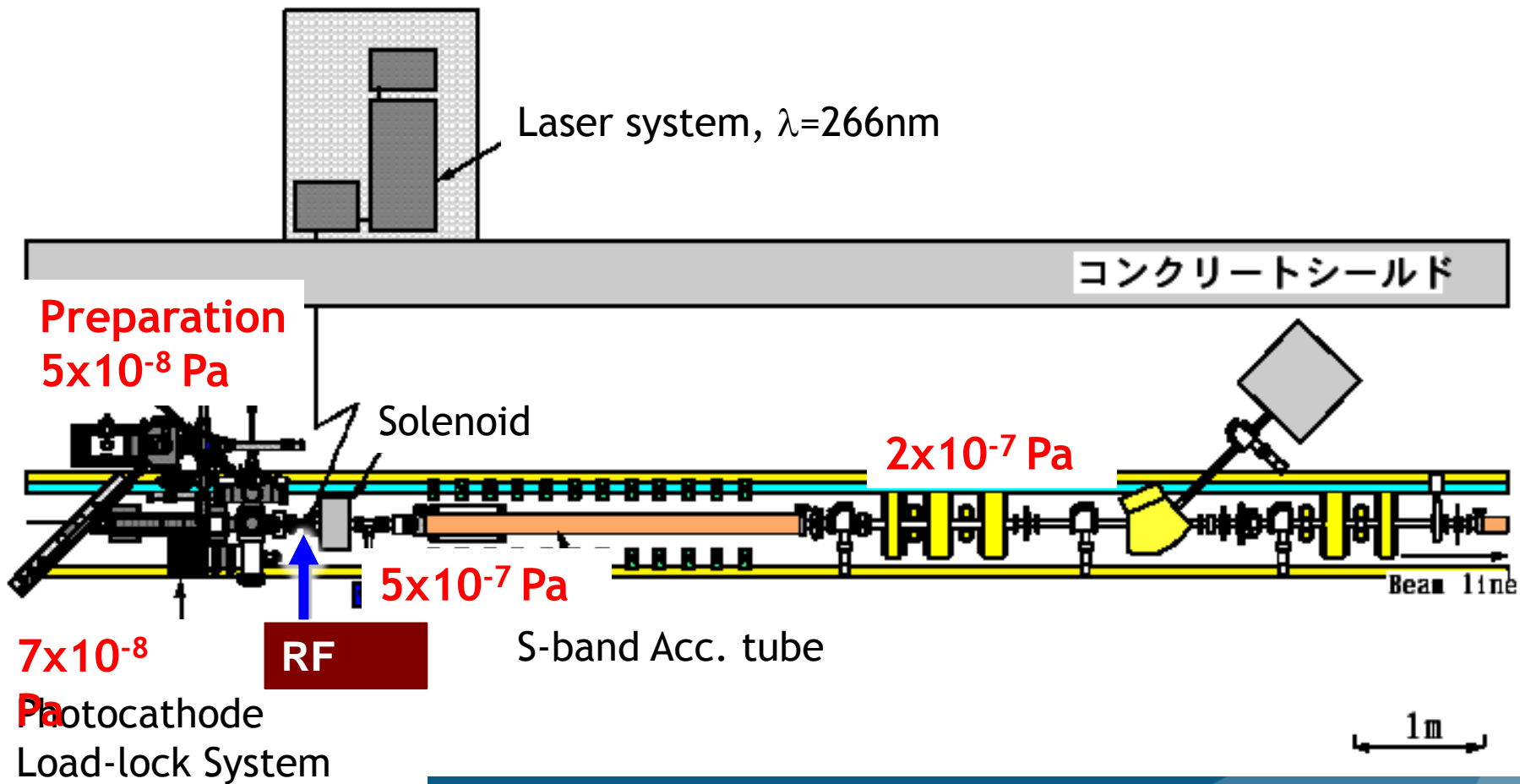
**QE (Quantum Efficiency)**

**= Number of electrons / Number of laser photons**

# Handling in vacuum

- $\text{Cs}_2\text{Te}$  photocathode should be handled in UHV to keep QE.
- How good vacuum is required?
- ATF RF gun:  $5 \times 10^{-7}$  Pa
- QEs of early samples after the vacuum work were low even if the pressure reached nominal level.
- QEs of later samples, after several  $\text{Cs}_2\text{Te}$  preparations, become better and better. Pressure was not improved significantly.
- Oxidation of the  $\text{Cs}_2\text{Te}$  layer is a major candidate of degradation of QE.
- Vacuum quality, amount of oxygen, should be considered.

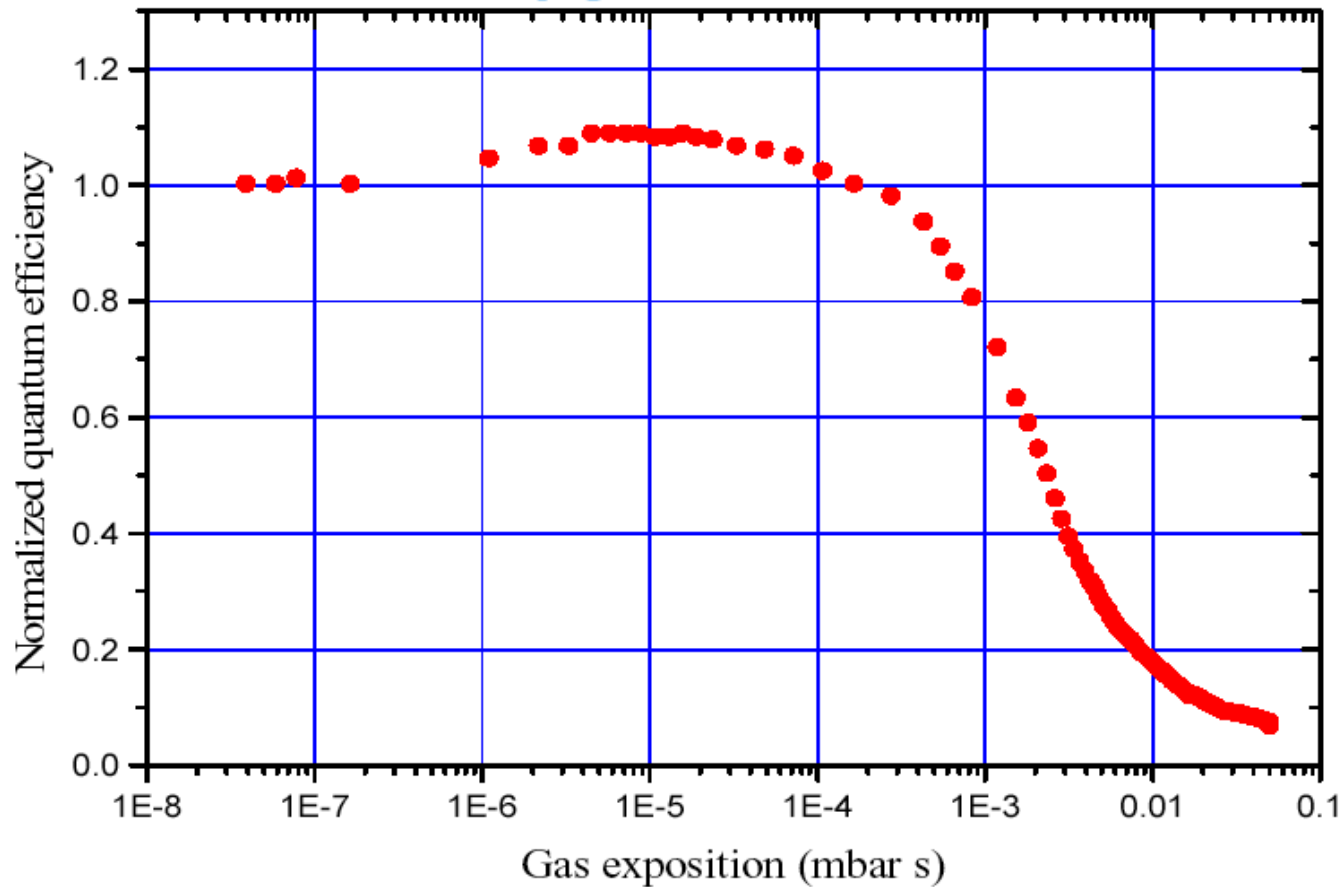
# Vacuum pressure around the ATF 80MeV Injector



# Handling in vacuum

TTF/DESY 2006

## Cs<sub>2</sub>Te response to Oxygen exposition

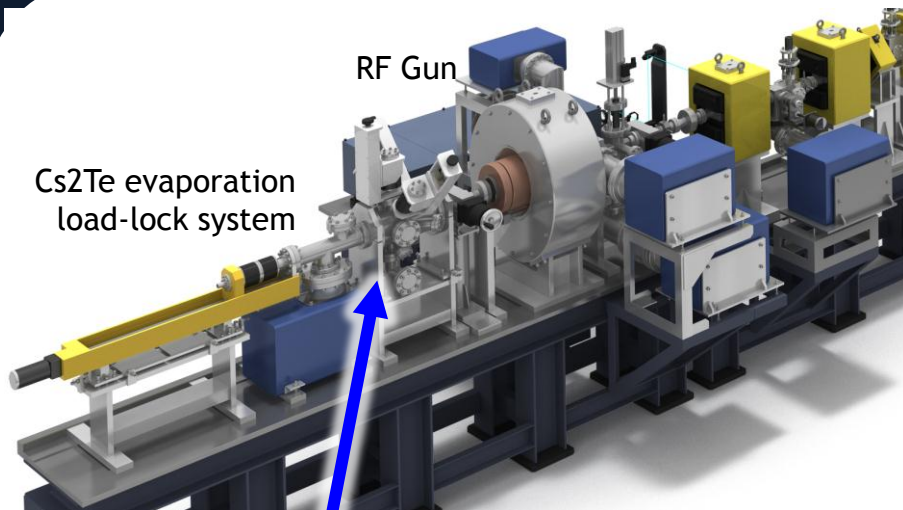




# Photocathode transport in vacuum

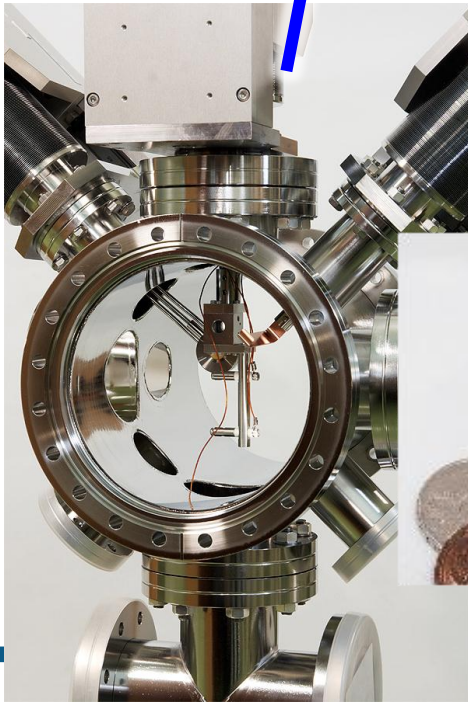
- STF system
  - continuous vacuum connection
  - preparation system is just behind the RF gun
- ATF system
  - continuous vacuum connection, sectioned by valves, between  $\text{Cs}_2\text{Te}$  preparation and RF gun
  - preparation system is far from the RF gun
- LUCX system
  - separated; cathode is transferred by in vacuum carrier

# STF photocathode system



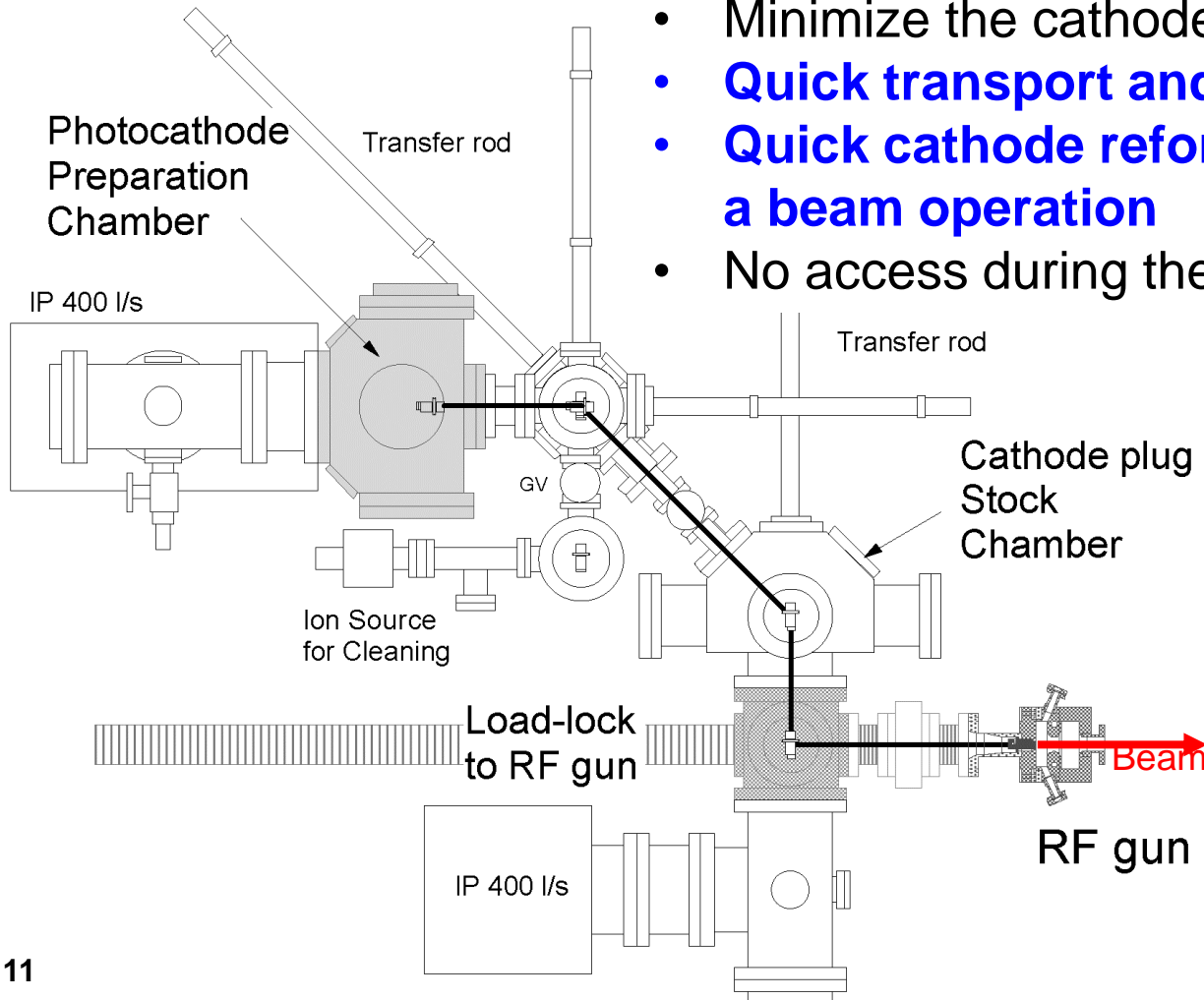
## L-band RF Gun Cs<sub>2</sub>Te Photocathode

- **Evaporation system**
  - similar method as ATF/LUCX
  - located behind the RF gun
- **Cathode plug**
  - Mo for cathode substrate
  - ceramic isolator
- **Laser**
  - Nd:YAG: 266 nm
  - 162.5 MHz, 1ms, 5 Hz
  - pulse width 12 ps
- **Cathode**
  - **Cs<sub>2</sub>Te QE: 0.2~0.5%**



# ATF Cs<sub>2</sub>Te photocathode preparation and load-lock system

- **No vacuum break transportation**
- Minimize the cathode oxidation
- **Quick transport and QE meas.**
- **Quick cathode reformation then resume a beam operation**
- No access during the ATF operation



**ATF**

**Cathode Load-lock System**

**Transport the photocathode under UHV**

**Cs<sub>2</sub>Te preparation**

**Cleaning & Pickup**

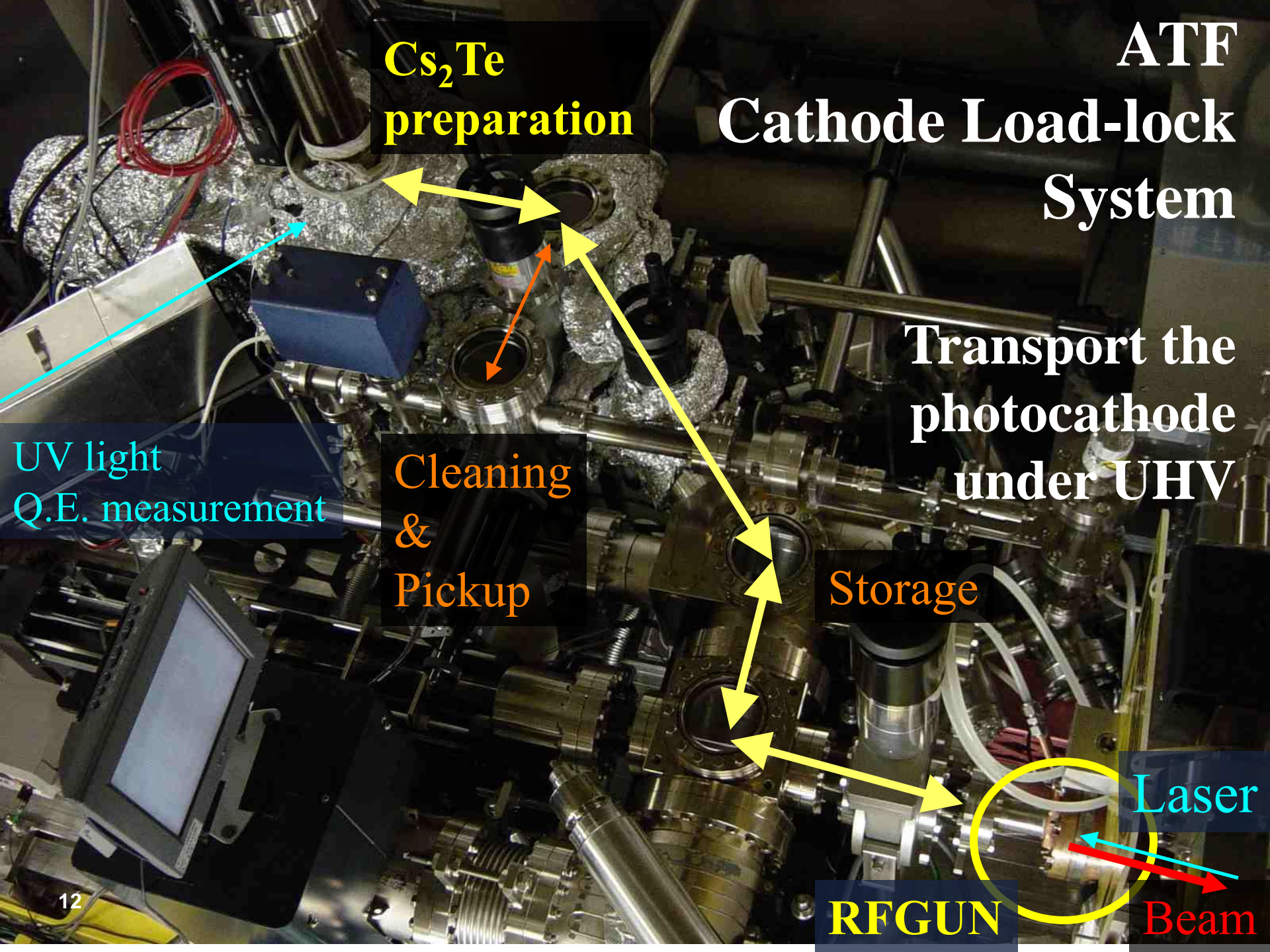
**Storage**

**Laser**

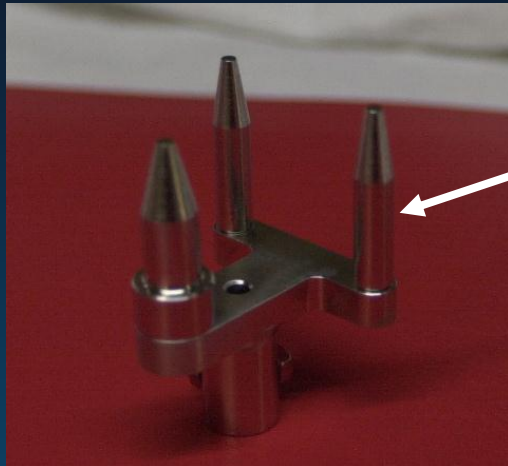
**Beam**

**RFGUN**

**UV light  
Q.E. measurement**

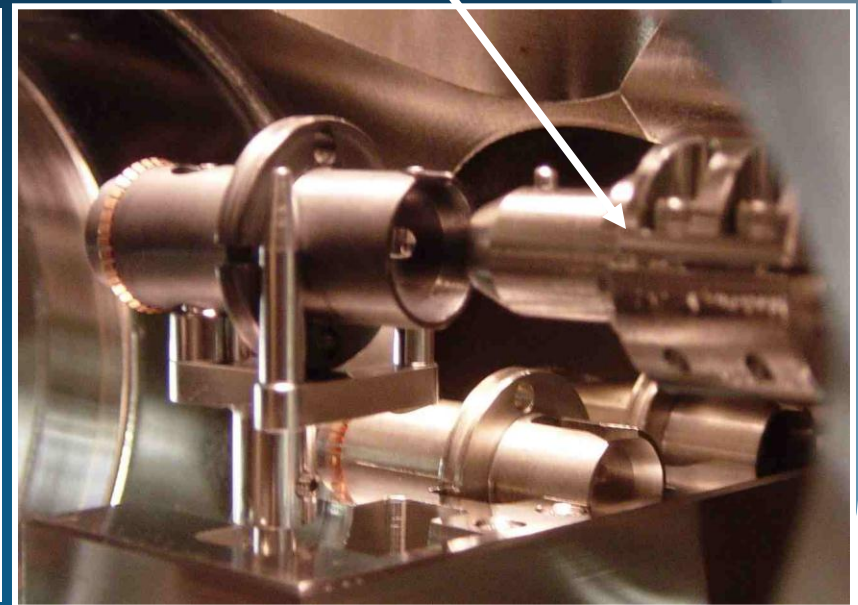
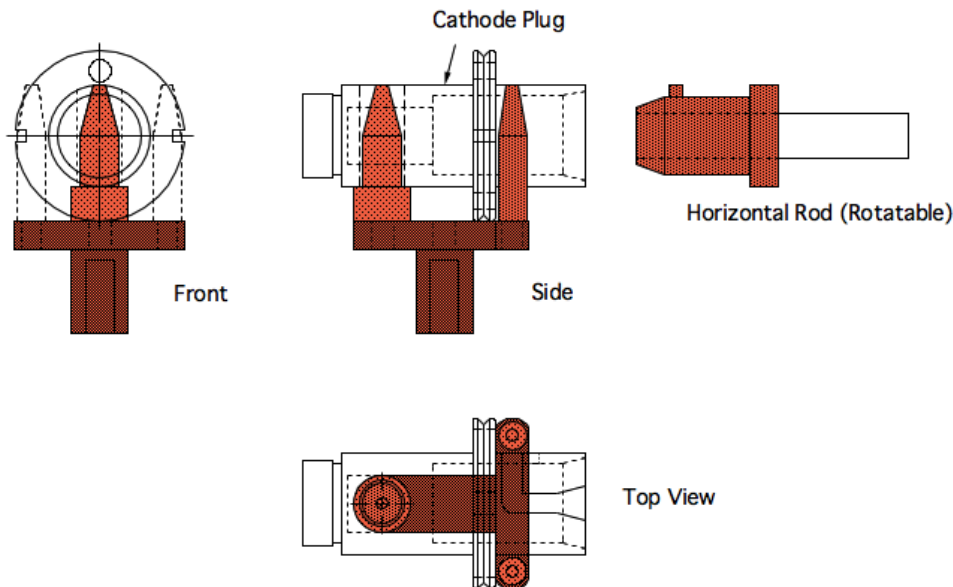


# Transport tools of cathode plug



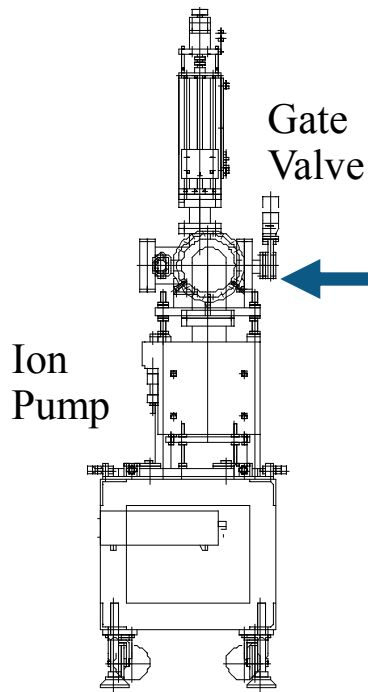
Plug mount for vertical rods  
Up/down and rotation

Horizontal rod  
Rotate to lock the cathode plug



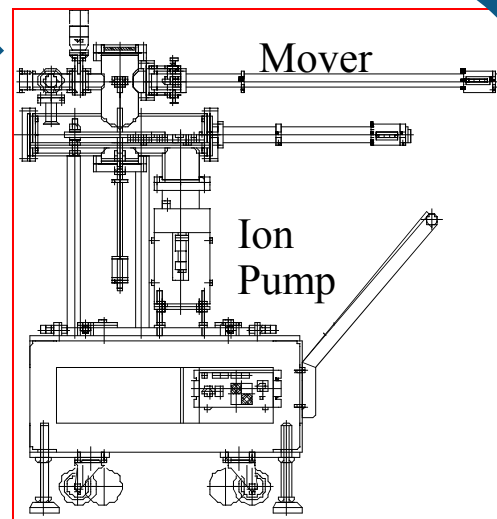
# LUCX photocathode system

Cs<sub>2</sub>Te Cathode formation system

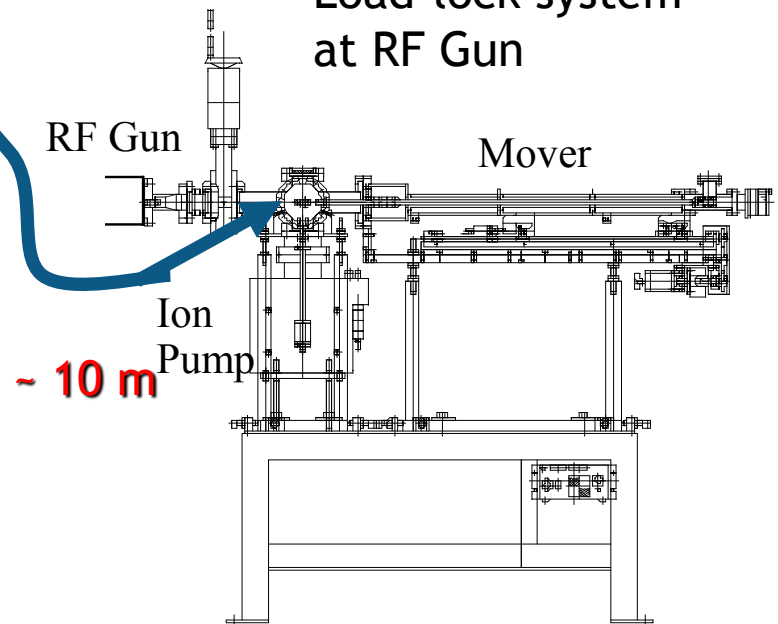


A carrier box with ion pump is also used to transport the cathode from KEK to Universities.

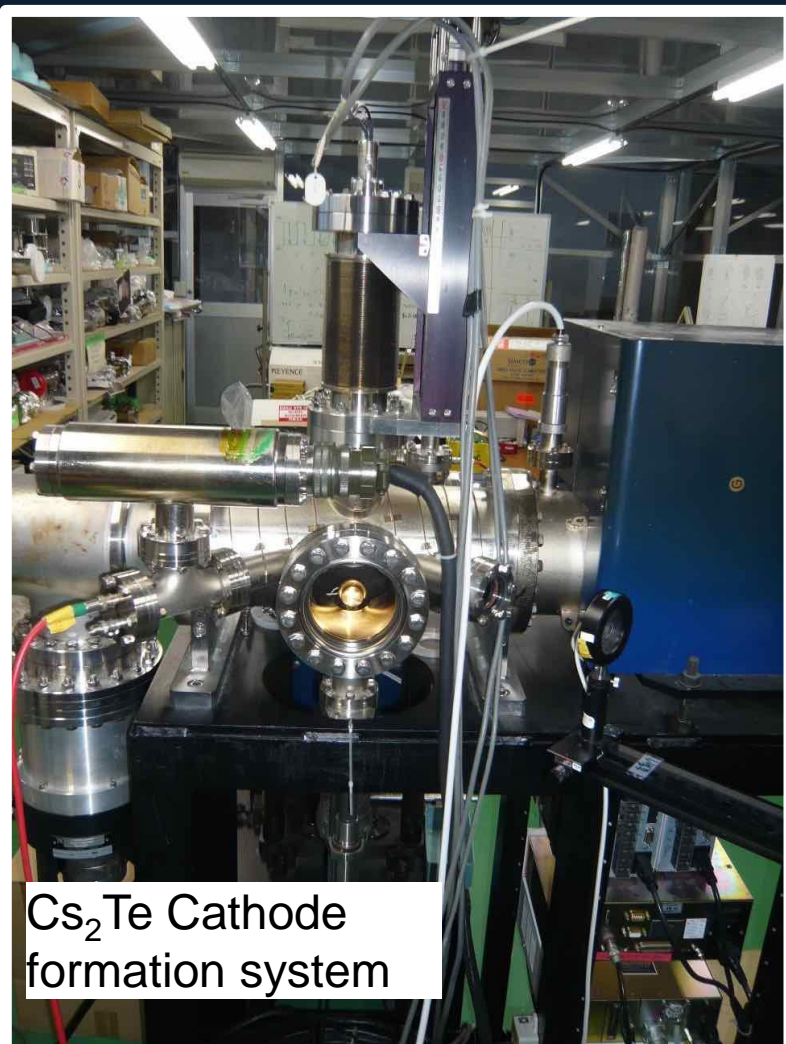
**Cathode in vacuum carrier**



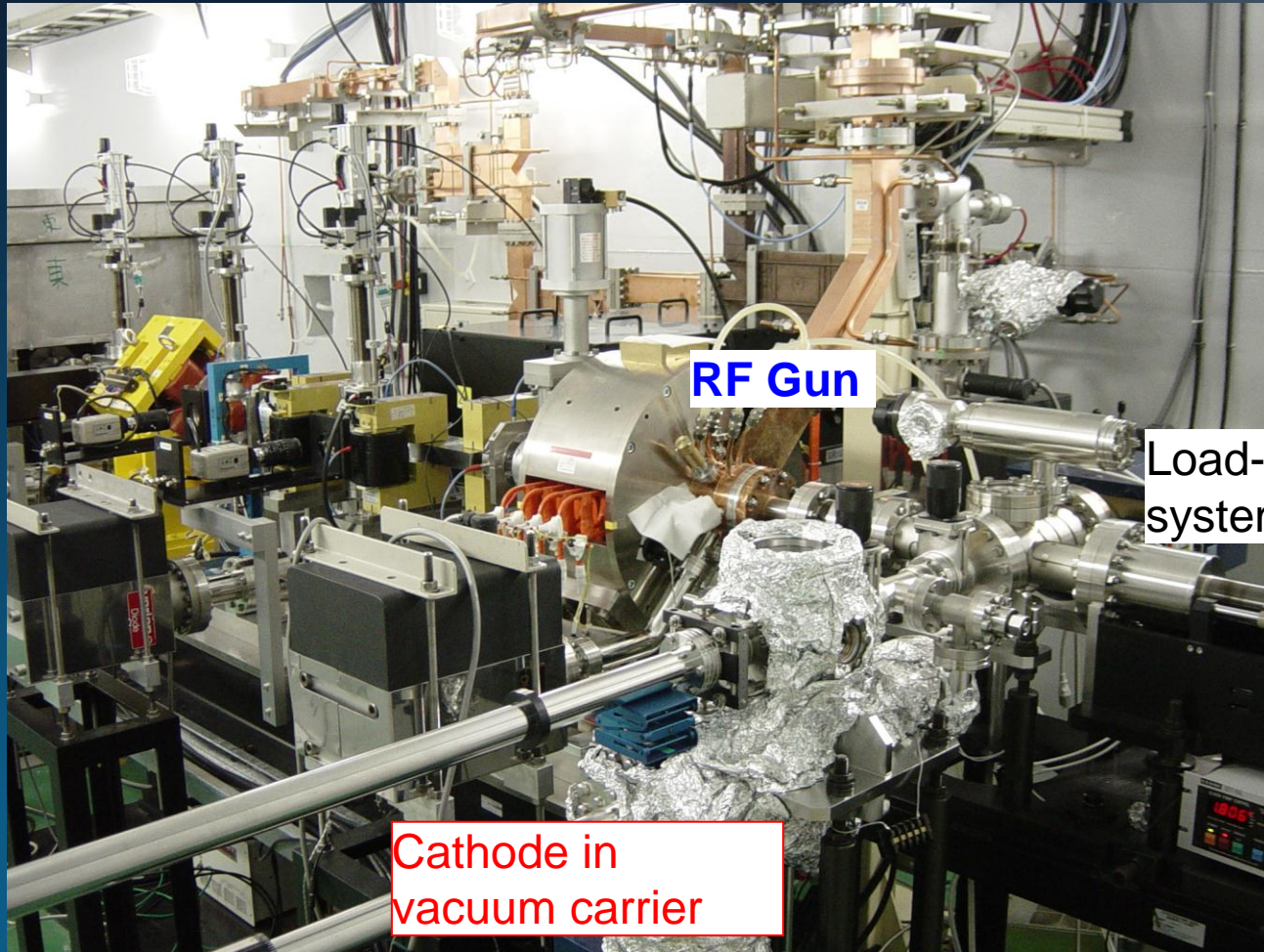
Load-lock system at RF Gun



# LUCX photocathode system



# LUCX accelerator and cathode transport



RF Gun

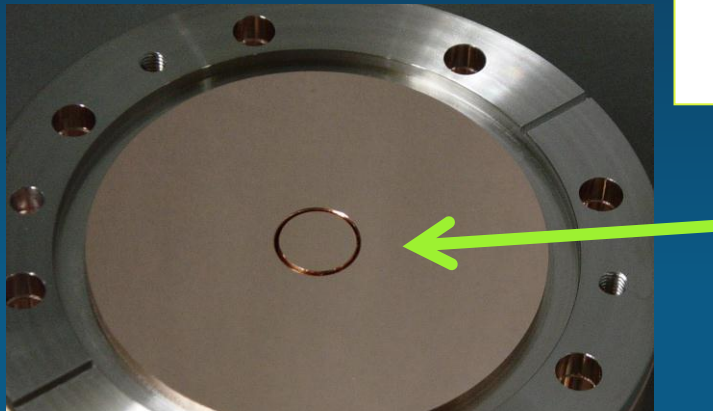
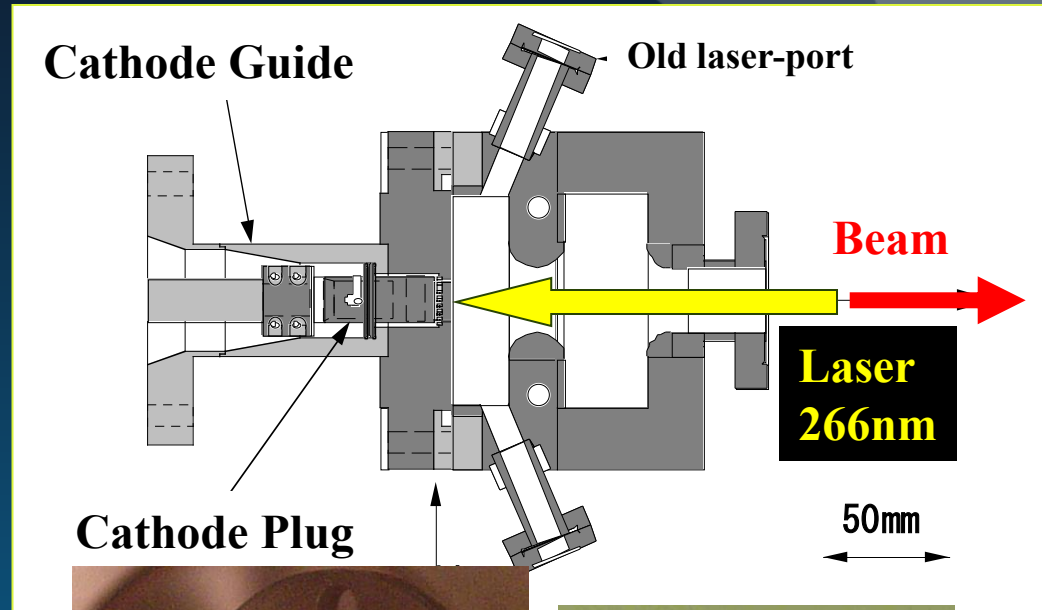
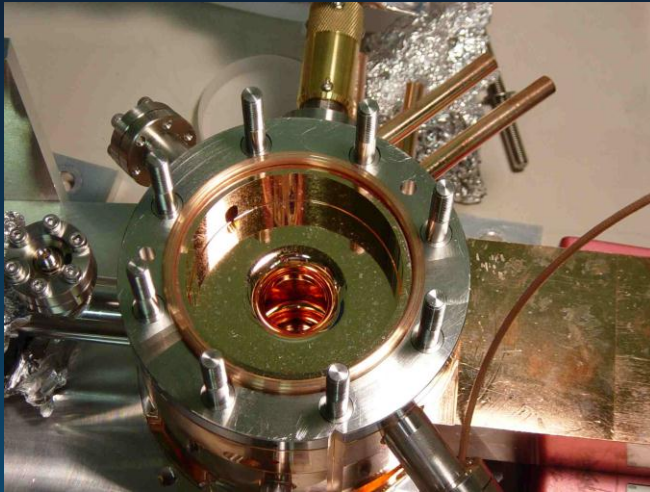
Load-lock system

Cathode in vacuum carrier

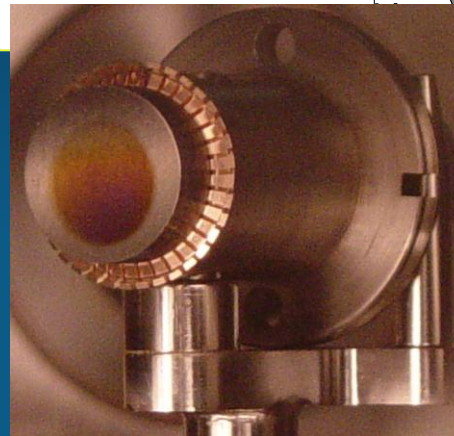


# How the photocathode attached on the RF gun? Example: First $\text{Cs}_2\text{Te}$ RF Gun at KEK

*Modified BNL type IV: 1.6 cell, 2856 MHz*

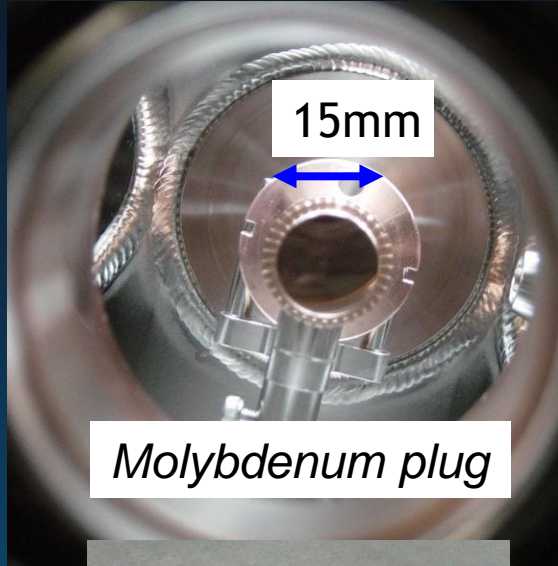


End-plate with Cathode plug



Spring Contactor

# Molybdenum substrate for Cs<sub>2</sub>Te



15mm

*Molybdenum plug*

**Mo is used for the cathode substrate.**

**Cu was also tried for the commissioning of the first Cs<sub>2</sub>Te RF gun at KEK in 2002.**

It shows **lower and unstable QE** compare to that of Molybdenum.

**Mo plugs for Cs<sub>2</sub>Te RF guns at KEK**

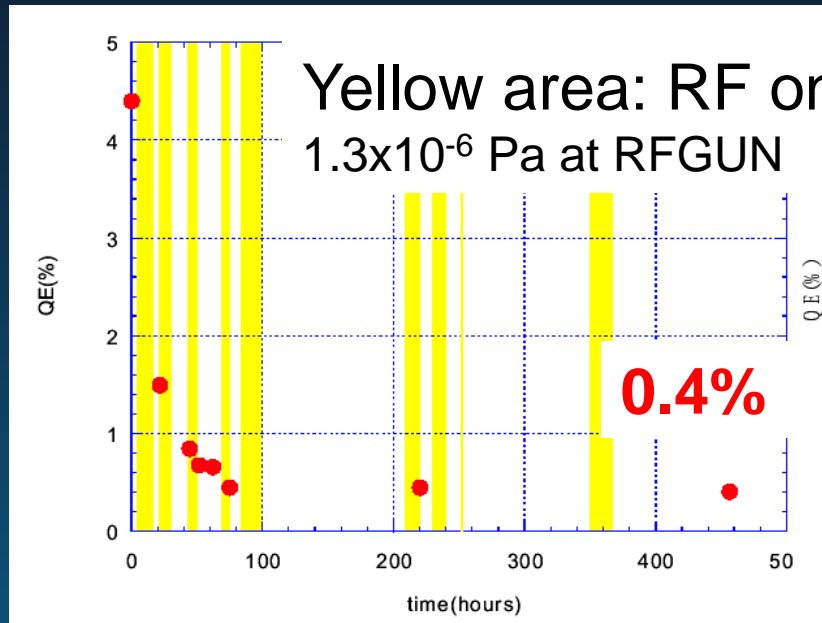
- **Mirror polished surface**
- Ultrasonic cleaning by Ethanol/Acetone after the machining.
- No other chemical treatment is applied.
- **Ar<sup>+</sup> ion or heat cleaning**



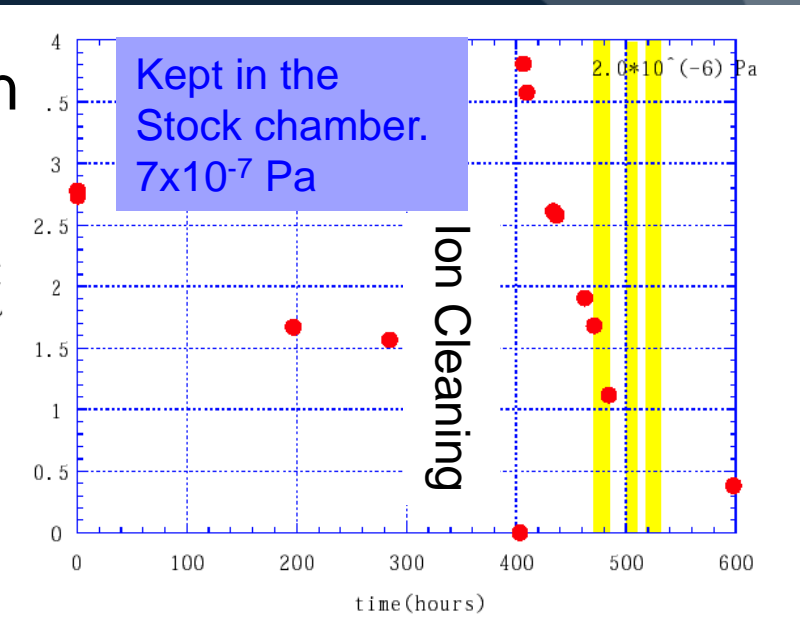
*Copper plug*

# QE of the $\text{Cs}_2\text{Te}$ photocathode on Cu

Cu-No.1

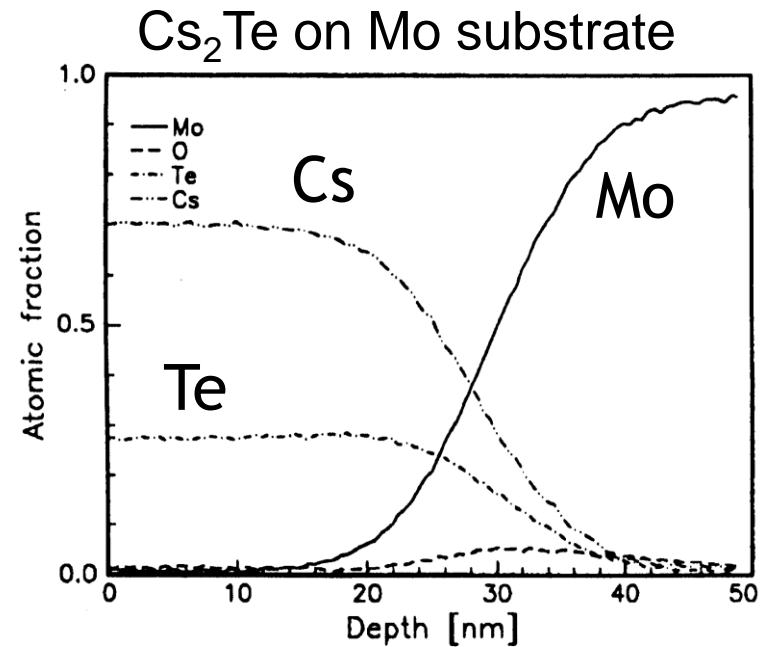
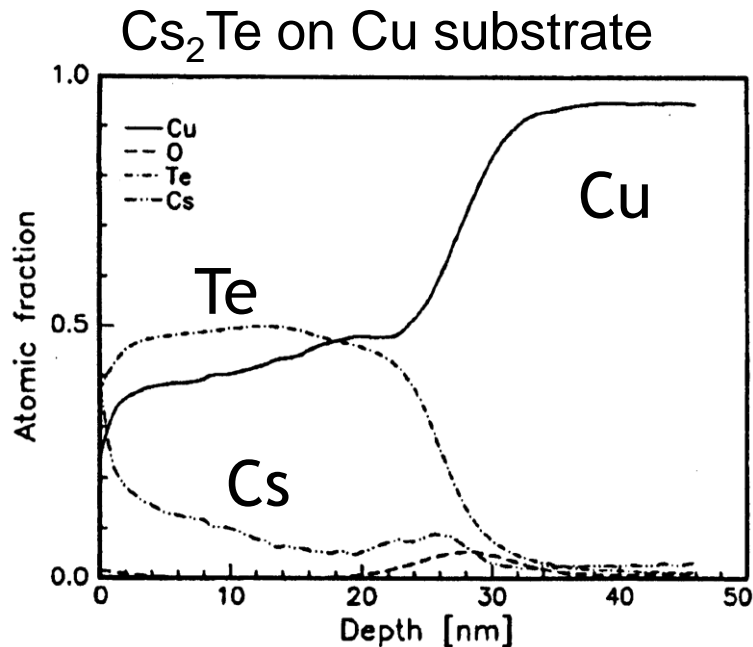


Cu-No.2



Vacuum pressure was not good at this commissioning stage but the later Mo sample showed 3% of QE under similar vacuum condition.

# Molybdenum substrate for $\text{Cs}_2\text{Te}$



*A di Bona et al., "Auger and X-ray photoemission spectroscopy study on Cs<sub>2</sub>Te photocathodes", J.Appl.Phys.80 No.5(1996)3024-3030*

**Auger analysis shows the ideal atomic fraction for Mo substrate.**  
It will be a reason of the higher QE than Cu substrate.

# Preparation of the Cs<sub>2</sub>Te photocathode

## Step 1: Surface cleaning

- Argon-ion sputtering is used for ATF to cleanup the substrate surface.
- No heat-cleanup because of the Be-Cu contact on plug.

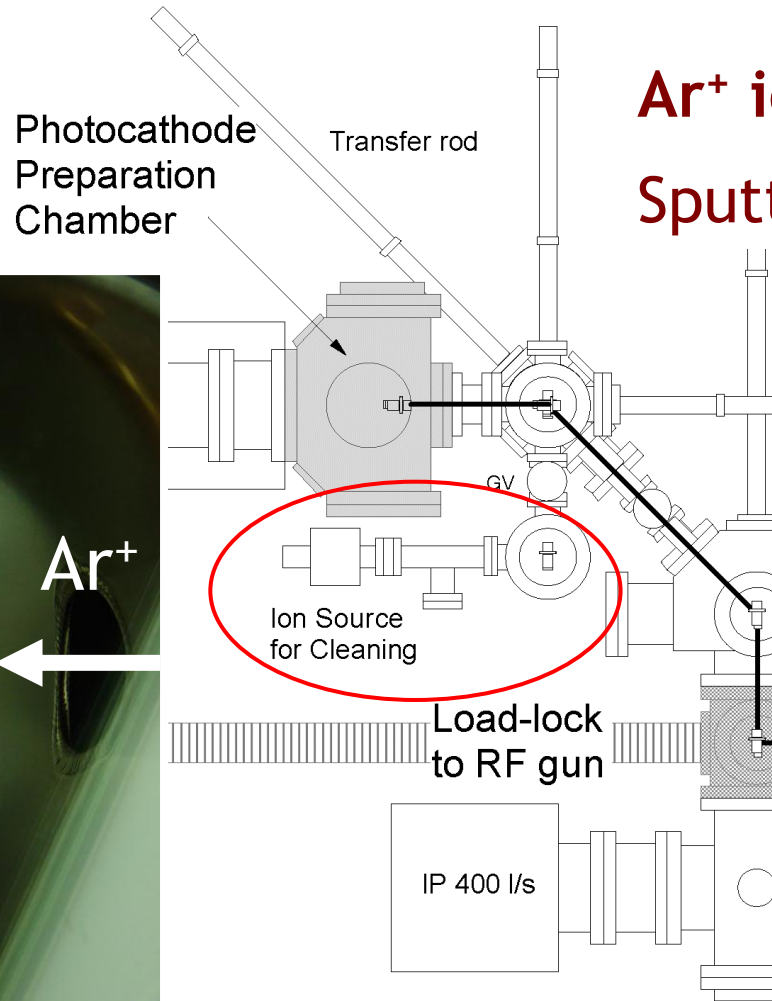
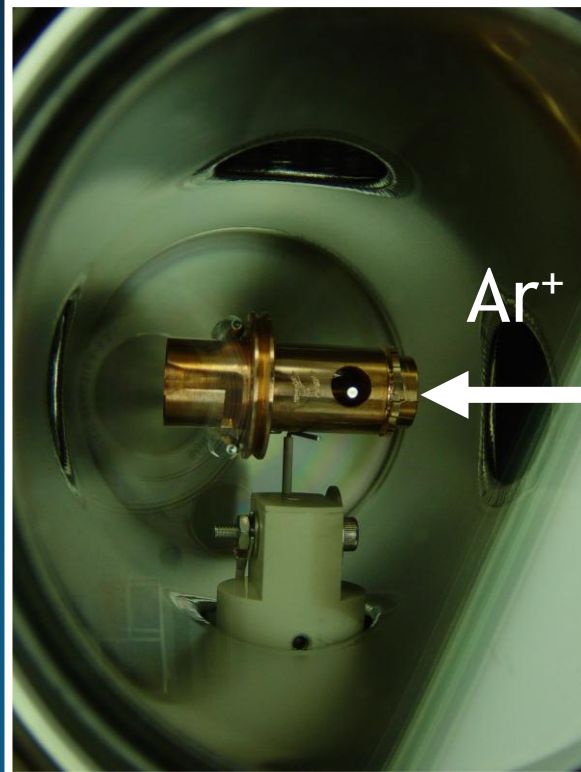
## Step 2: Tellurium layer formation

- Amount of Te is controlled by monitoring the thickness on the sensor located at the equivalent distance.

## Step 3 : Cesium deposition on Te layer

- Amount of Cs is controlled by monitoring the quantum efficiency.

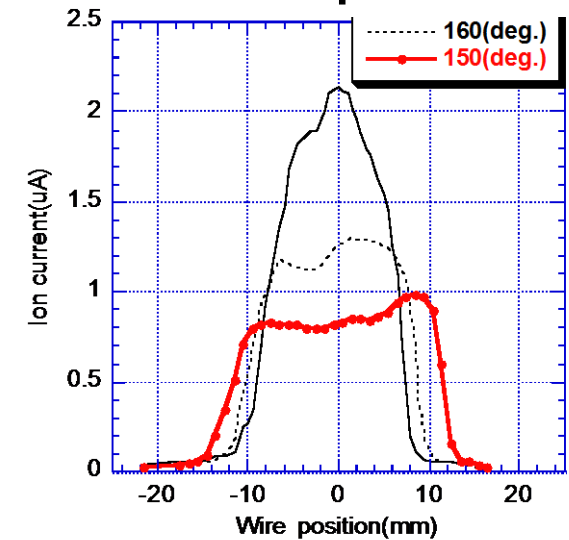
# Step 1: Surface Cleaning before $\text{Cs}_2\text{Te}$ formation



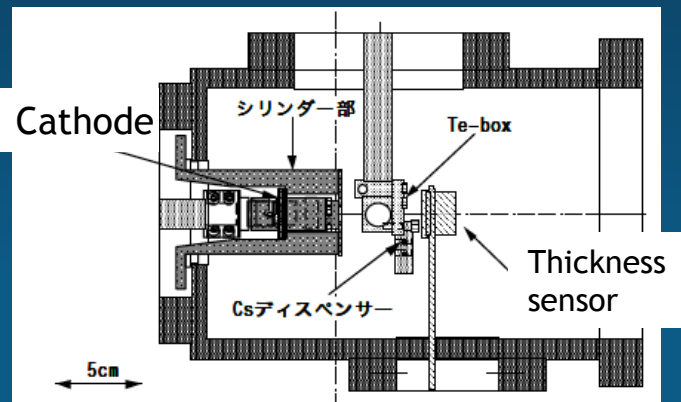
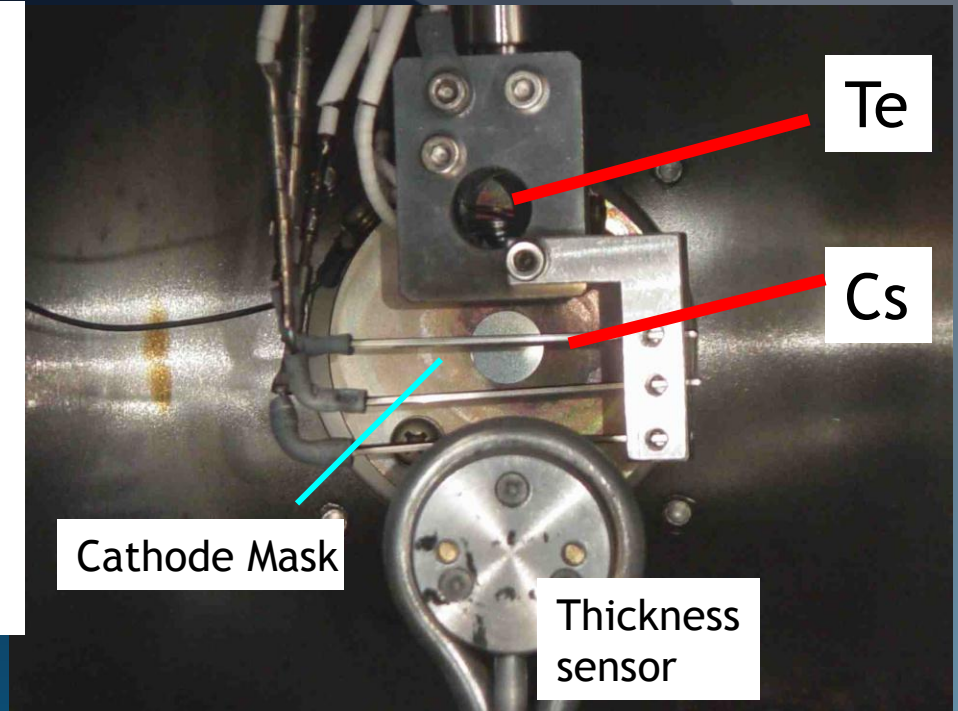
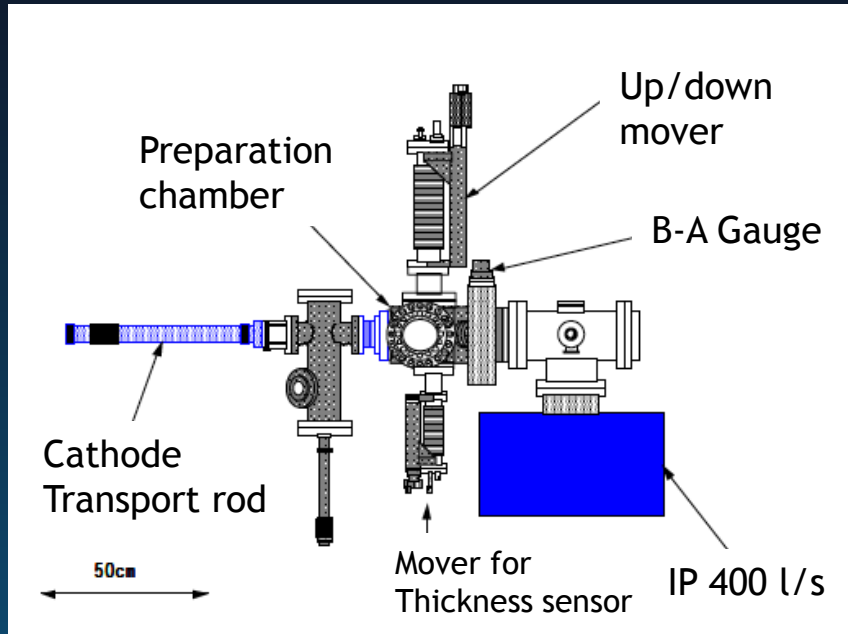
**$\text{Ar}^+$  ion bombardment**  
**Sputter depth ~50nm.**

Transfer rod

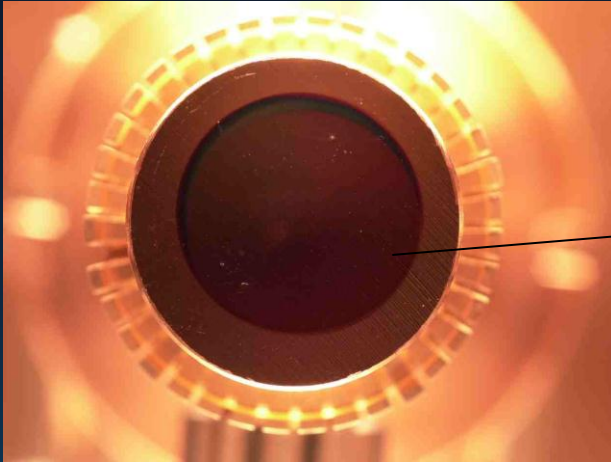
**$\text{Ar}^+$  ion profile**



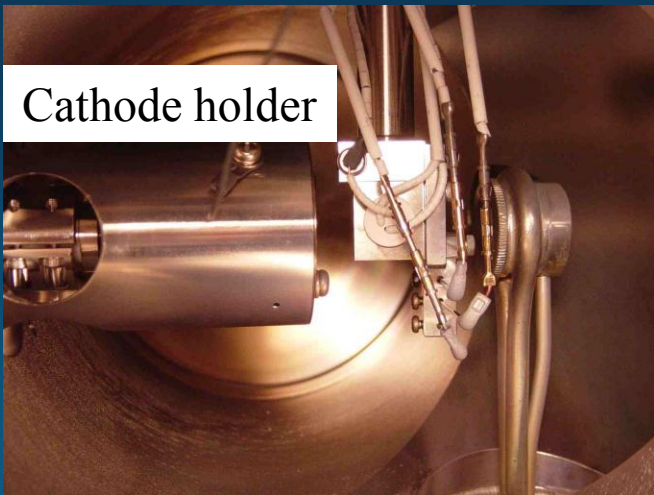
# Te and Cs sources



- Select Te or Cs by moving up/down
- Short cyclic up/down to make a uniform evaporation.

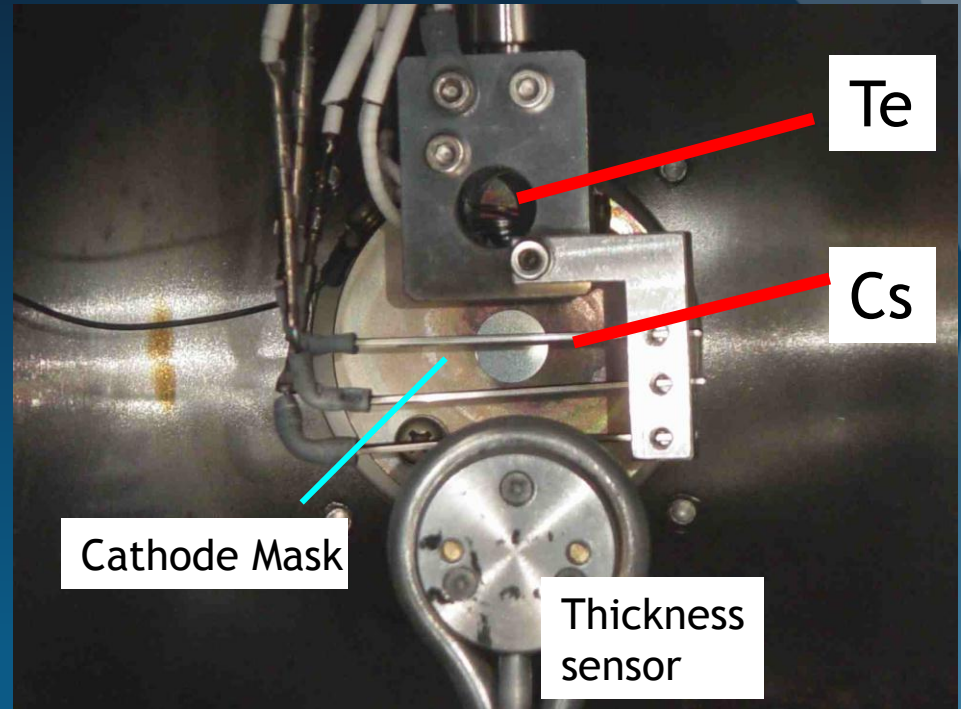


- Put the cathode plug in the cathode holder.
- Mask with  $\phi$  10mm hole prevents the surface edge from the evaporation of Te and Cs.



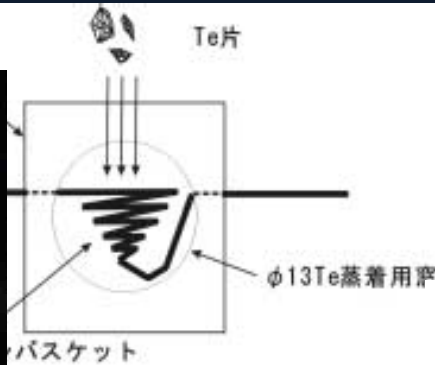
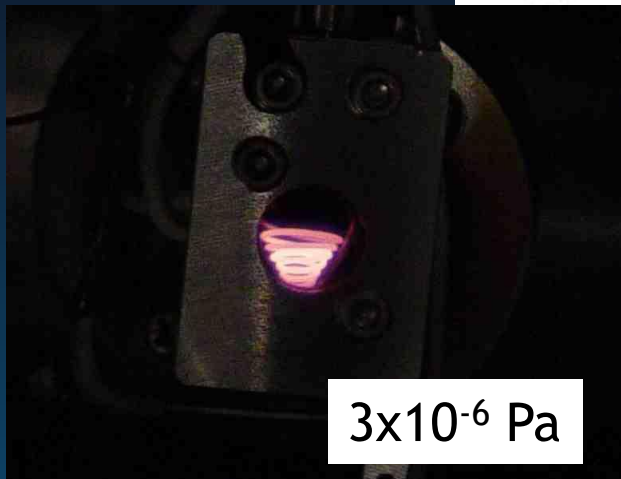
Cathode holder

Side view

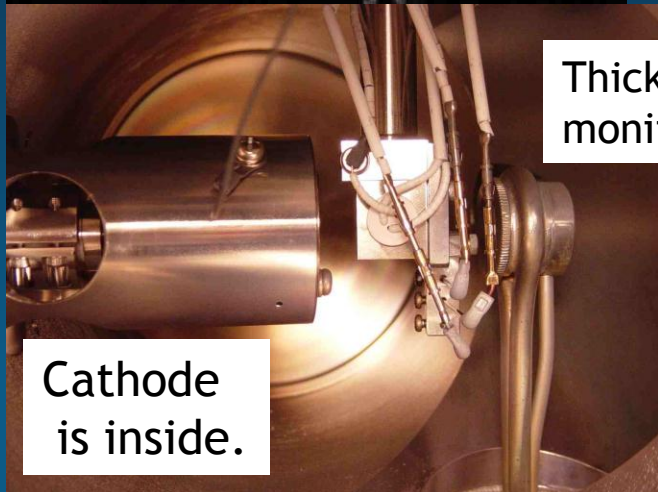
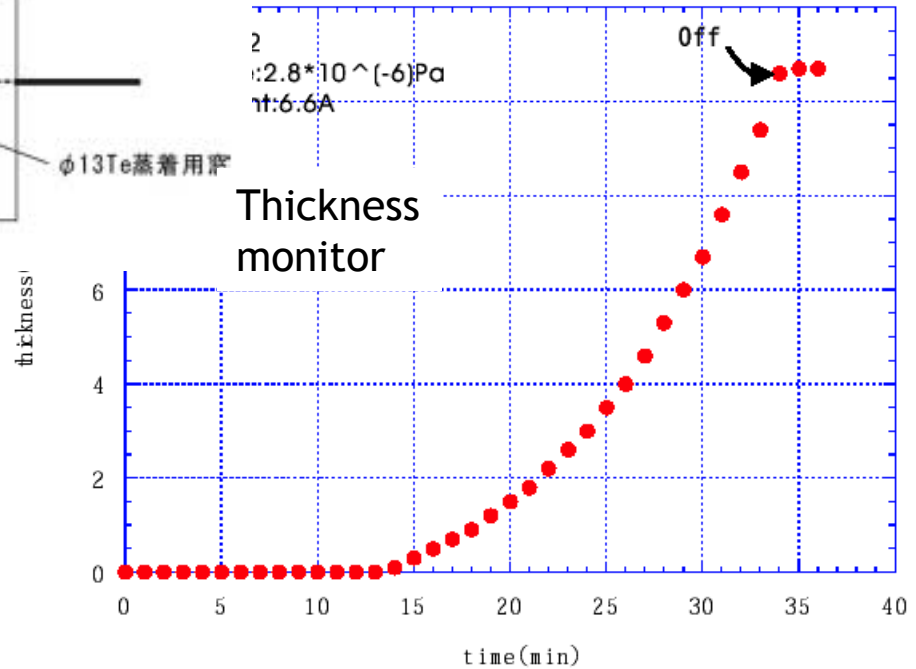




# Step 2: Tellurium layer formation



Te evaporation

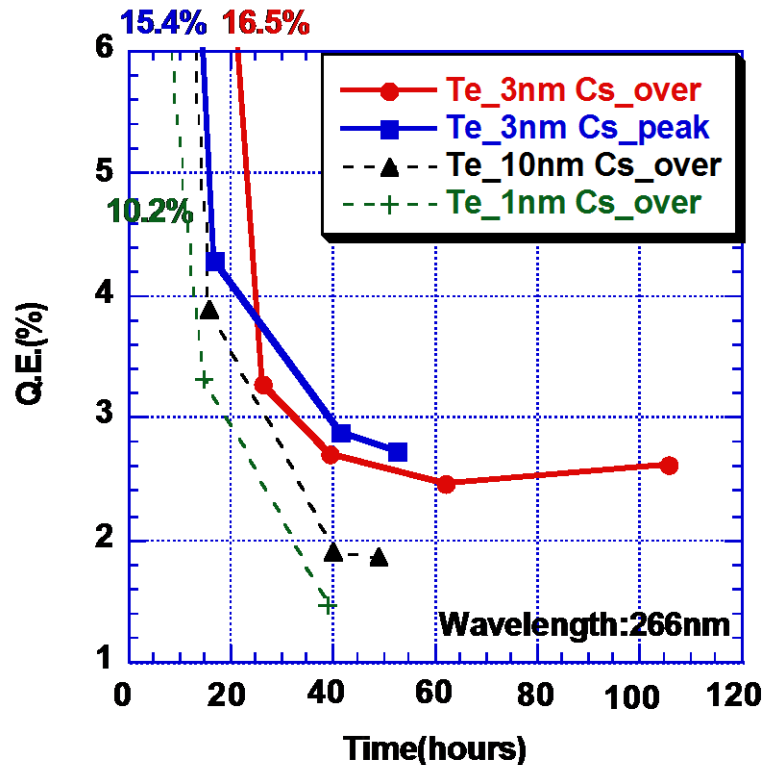


Thickness monitor

- Te is heated by a Tungsten filament.
- Control the Te thickness by monitoring the thickness coated on the sensor placed at equivalent distance.

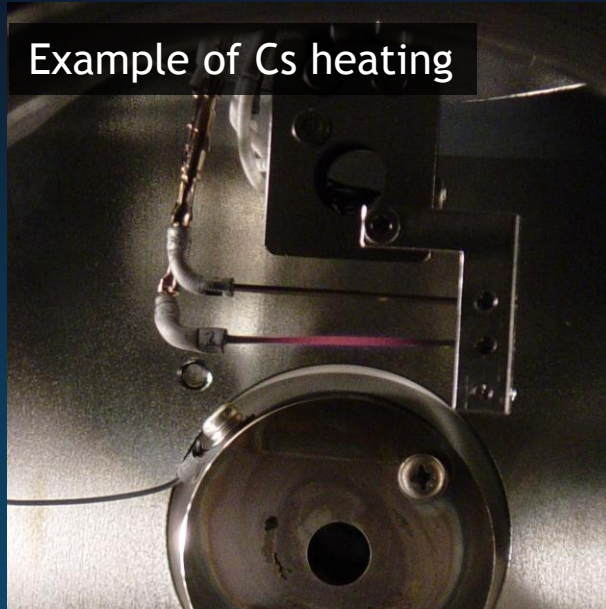
# Te thickness dependence on QE

QE measured under the RF intervals

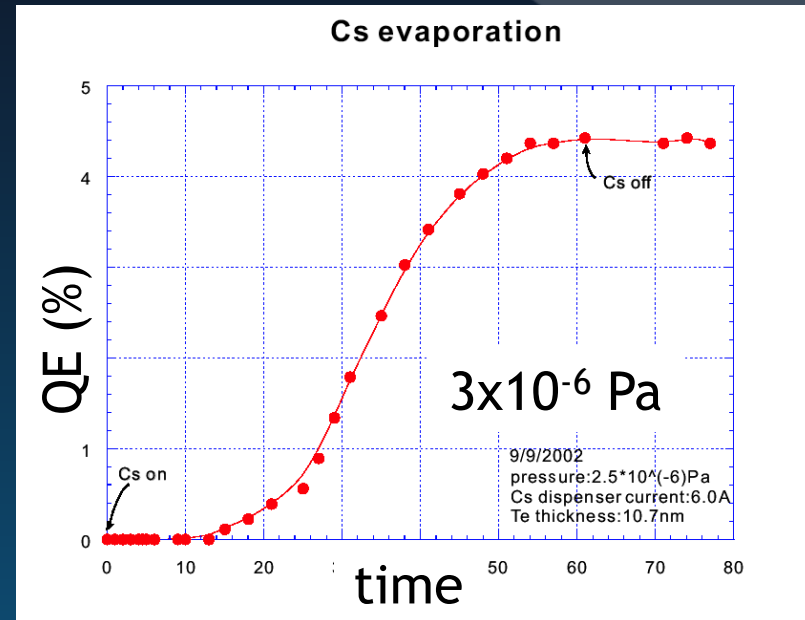


- QE was measured by several hours RF operations.
- Not enough samples indeed
- Results in 2003 showed better QE for the 3 nm sample.
- Sometimes Te-piece tipped in the filament bucket, then several 10 nm of Te was formed accidentally.
- **Typical Te thickness for ATF operation is more than 10 nm but less than 100 nm.**
  - It may be much safe for the RF breakdown in the Gun.

# Step 3: Cs deposition on Te layer

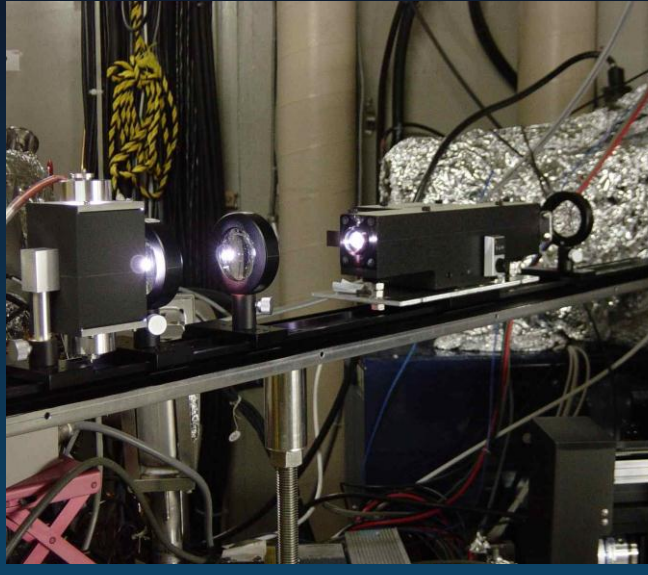


Cathode holder with Mask  $\phi 8\text{mm}$

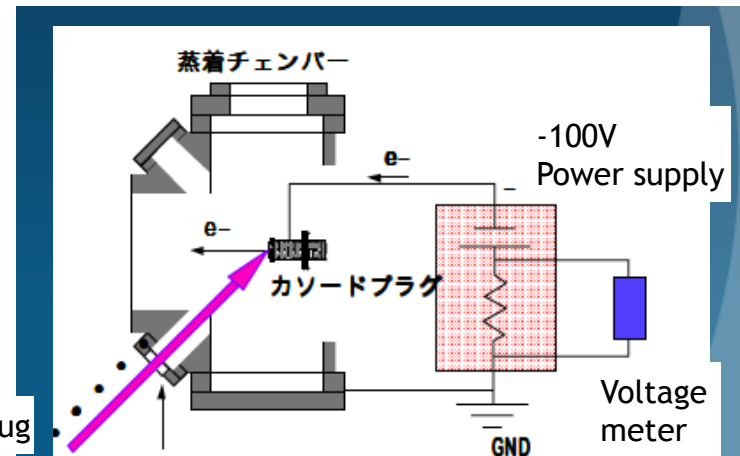
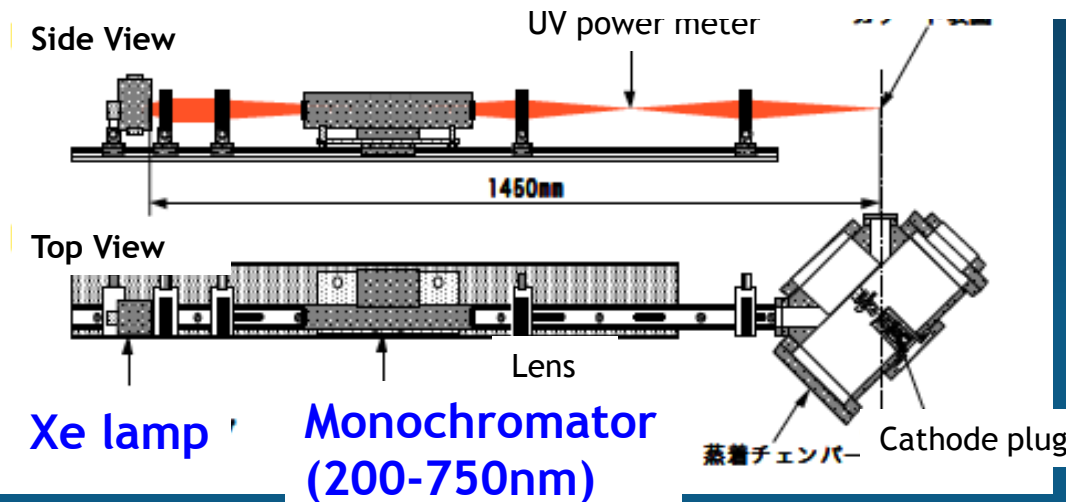


- Control DC current on Cs dispenser.
- One-side evaporation; no thickness monitoring (at ATF)
- Amount of Cs deposition is determined by monitoring the running QE.

# Measurement of QE



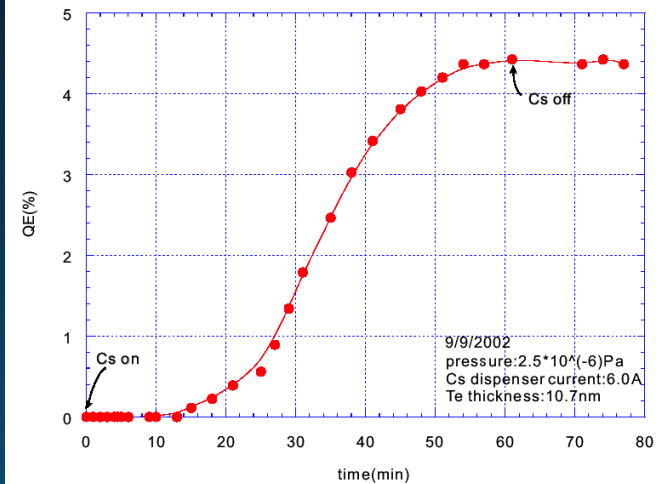
- **QE can be measured when a cathode plug is in the  $\text{Cs}_2\text{Te}$  preparation system.**
  - Quick measurement after RF operation
  - No measurement is possible under a beam operation.
- Monochromator and Xe lamp  $\rightarrow$  266 nm(laser)
- Measure the photo-emission current by monitoring the drop of voltage on the cathode.



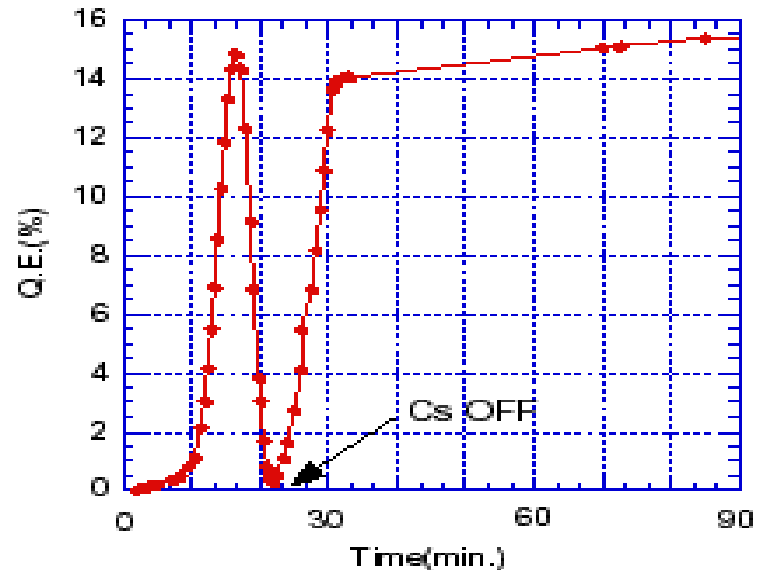
# Cs diffusion into the Te layer

## Slow Cs deposition

### Cs evaporation



## Fast Cs deposition

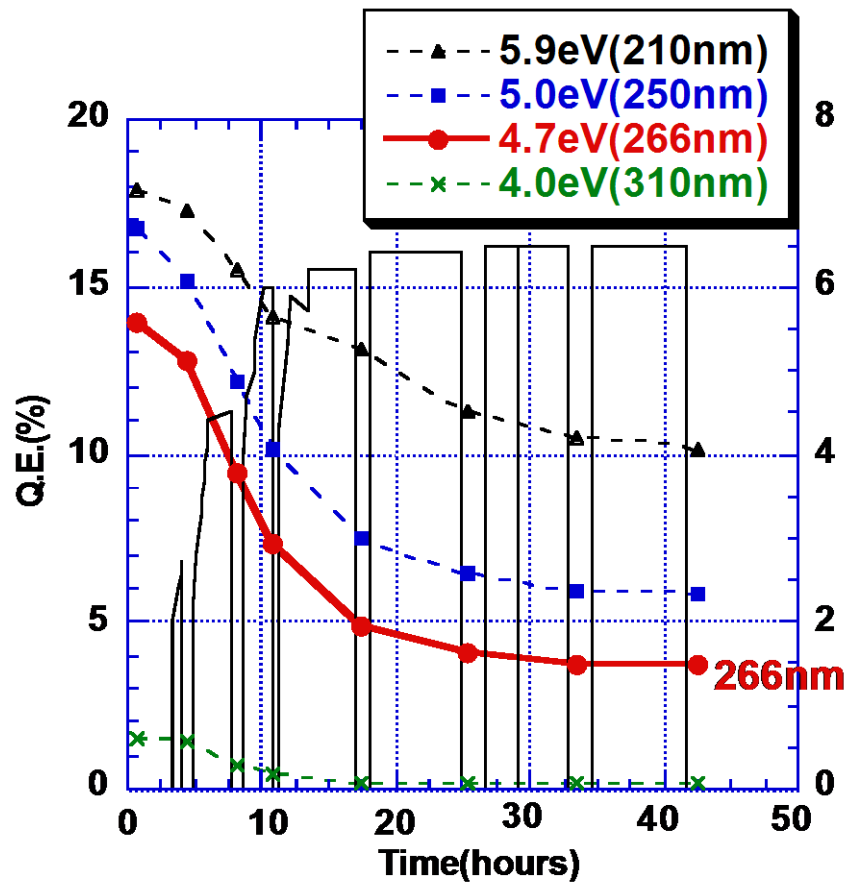


- Slow deposition samples showed the smooth saturation curve on QE . It may suggest the well-formed and stable Cs<sub>2</sub>Te layer.
- Fast deposition makes a Cs-rich surface at a moment and QE drops quickly. Then QE is recovered by following the diffusion of Cs into the Te layer.

# Experience of the Cs<sub>2</sub>Te photocathode with RF gun

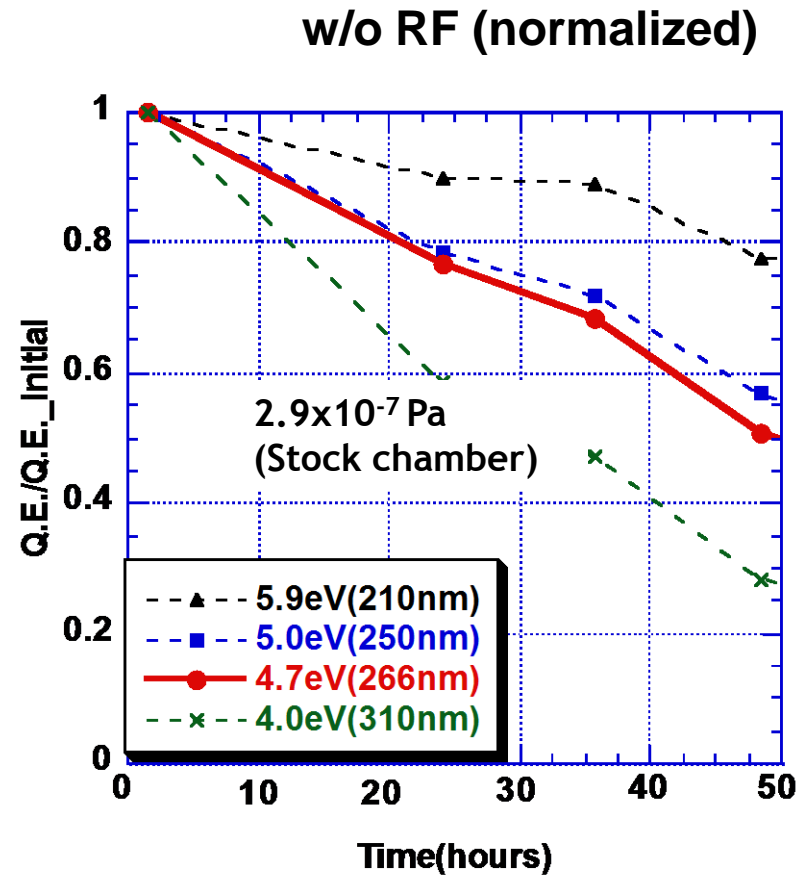
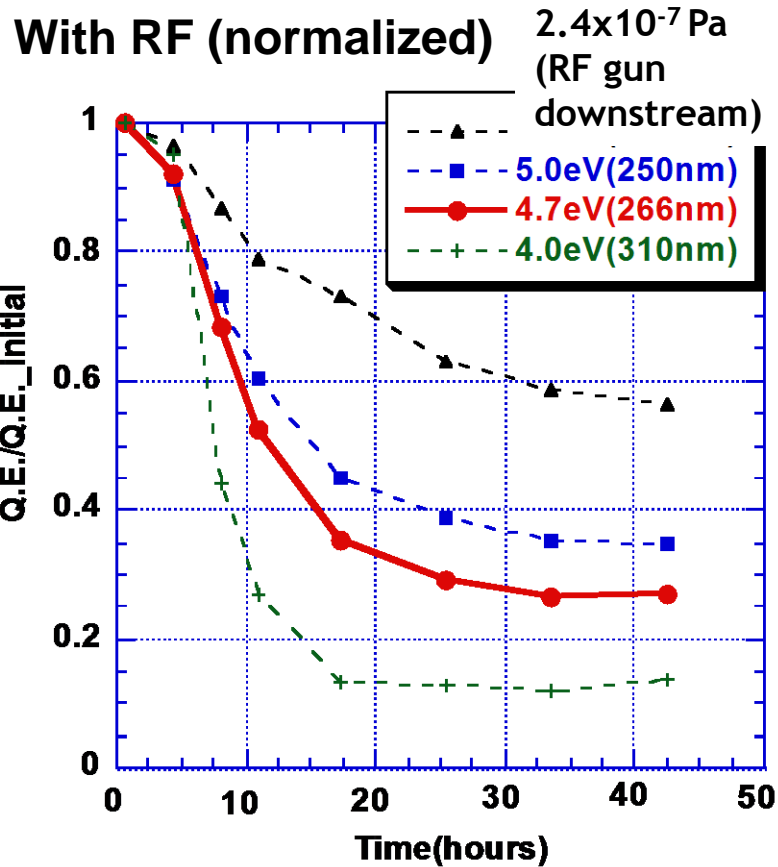
- Quick QE degradation under the RF field was observed
- QE was measured as a function of RF exposure
- Stable QE about a few % was obtained
- Long-term experiences

# Quantum efficiency under the RF field



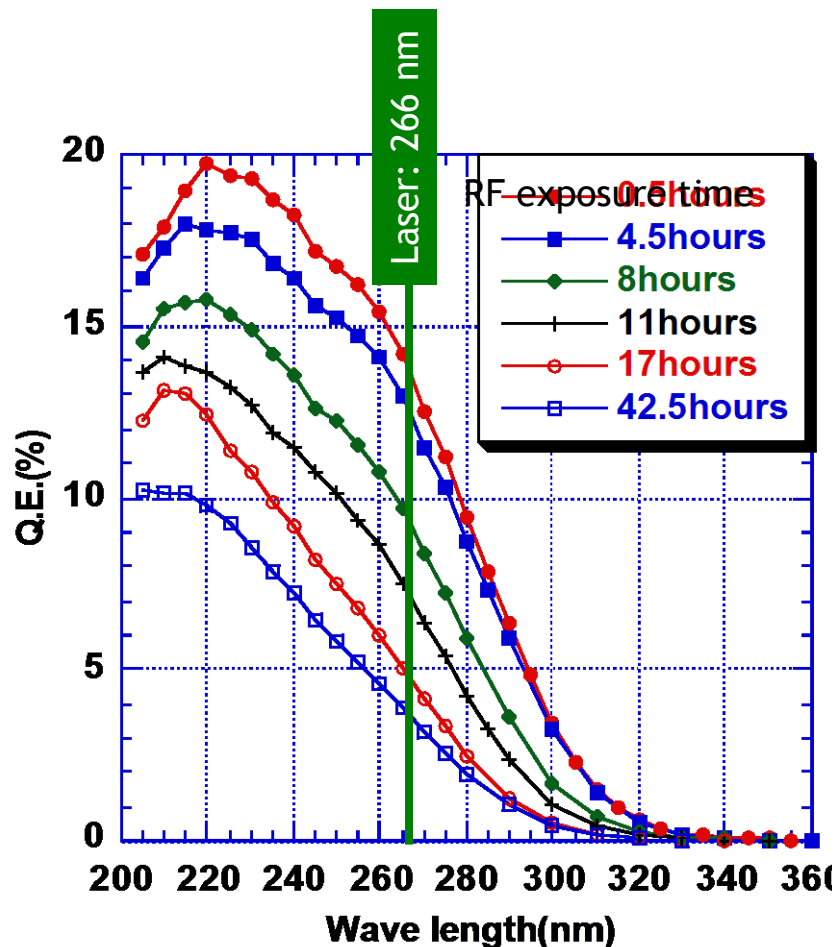
- Initial QE was sufficiently high ~ 14 %.
- **It drops quickly and reaches stable level when the RF is fed into the RF gun.**
- All QE measurements were done by moving the photocathode from the RF gun to the Cs<sub>2</sub>Te preparation chamber.

# Quantum efficiency under the RF field





# Wavelength dependence of QE for Samples exposed by RF

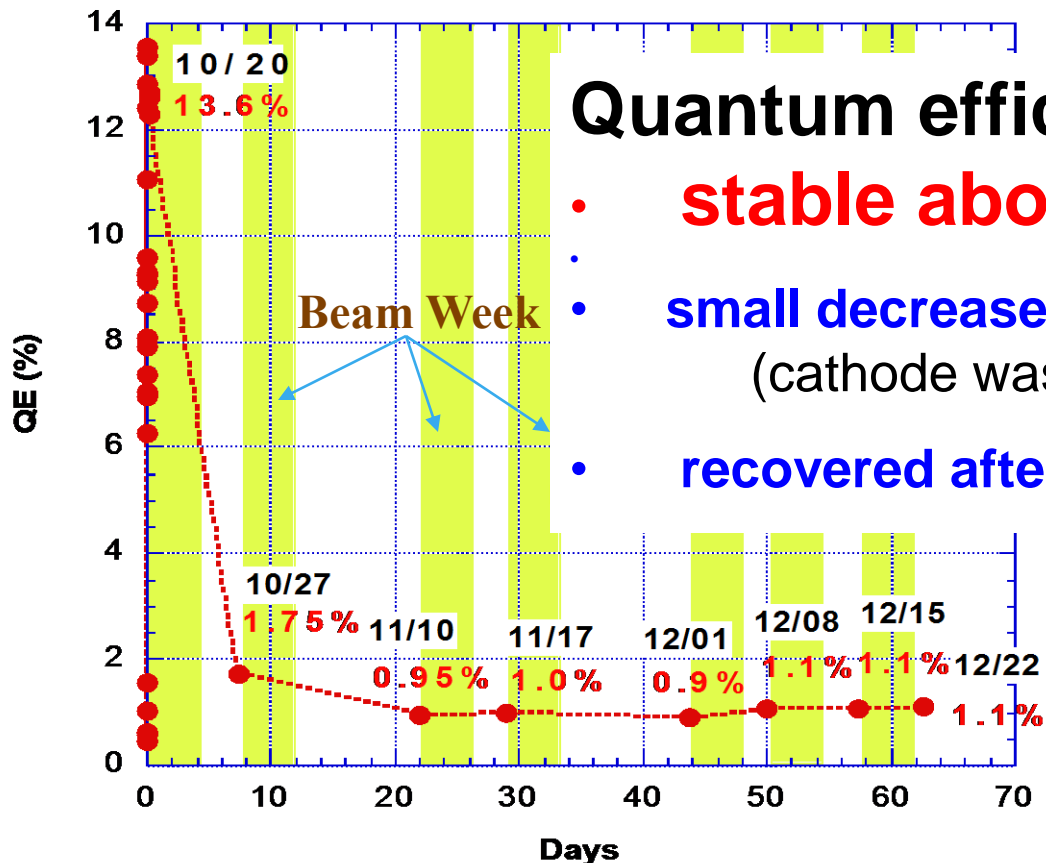


- QE degradation: all wavelength
- Peak shifts to shorter wavelength (higher energy)
- It may suggest the electron affinity of photocathode is changing.
- Not a physical damage?
- Oxidation by worse vacuum under RF?

# Photocathode: Long-term examples

# Two months history of the quantum efficiency under the ATF operation

Sample Mo#0, Eva. 2003-OCT-20  
Beam Operation 2003-OCT-20 to 2003-DEC-22



Quantum efficiency was ...

- **stable about 1%.**
- **small decrease in the shutdown week?**  
(cathode was kept in the RF gun.  $5 \times 10^{-7}$  Pa)
- **recovered after the beam generation?**

# Reforming the $\text{Cs}_2\text{Te}$ on the used photocathode

## Cleaning then forming the $\text{Cs}_2\text{Te}$

- same as brand-new cathode as expected; QE more than 10%.

## Forming the $\text{Cs}_2\text{Te}$ without cleaning

a few samples after several-months operation were tried reforming without cleaning.

### Case 1: both Te and Cs

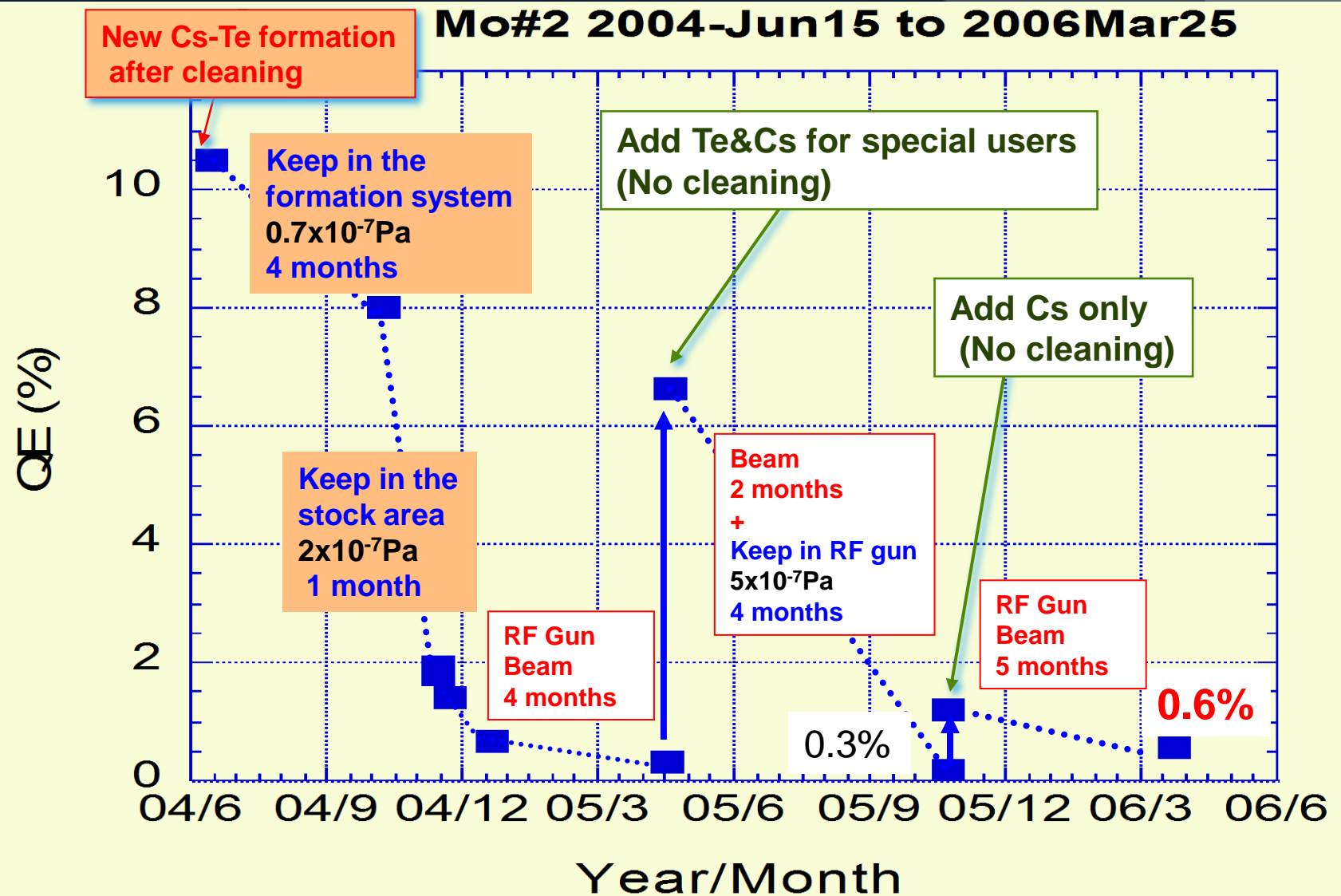
QE was recovered but less than 10%; i.e., 0.4% → 6.7%.

### Case 2: Cs only

not recovered well; QE 0.3% → 1.2%.

We did the cleaning in general but Cs only for sudden request of high intensity beam in the past.

# Reforming the Cs<sub>2</sub>Te on the used photocathode



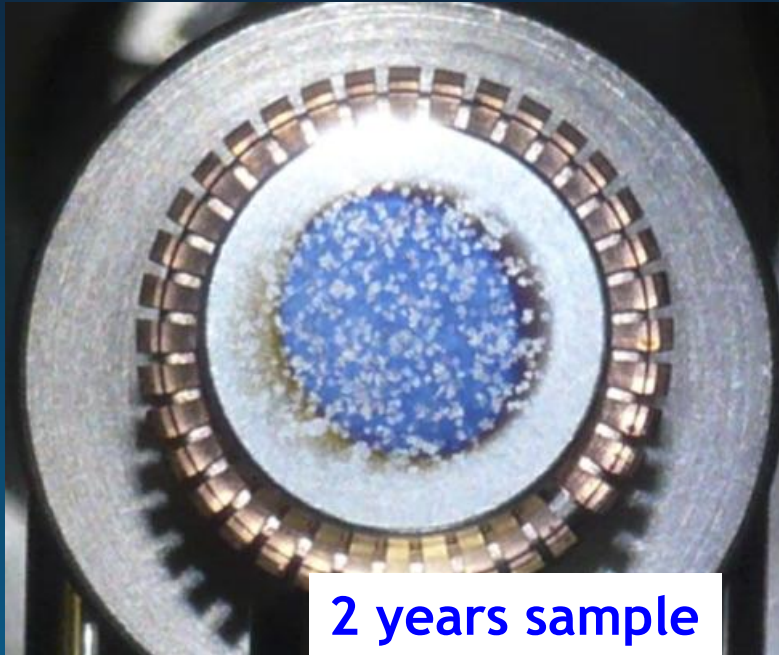
# More long-term (years) experience at ATF

- We have two long-term samples.
  - a sample of **two years** operation
  - a sample of **three years** operation (presently used)

**Both of them shows the stable quantum efficiency more than 0.5% (likely ~1%).**

- Surface
- Dark current with  $\text{Cs}_2\text{Te}$

# Cathode surface after long-term operation



- A lot of small spots were observed.
- They were scattered over the plug surface.
- somehow much on the  $\text{Cs}_2\text{Te}$  area (??)
- **~1% of QE was confirmed with these spots**
- We are not sure that spots are due to  $\text{Cs}_2\text{Te}$  because we have no long-term sample without  $\text{Cs}_2\text{Te}$ .

# Summary

- Cs<sub>2</sub>Te photocathode system at KEK are presented.
- More than 10 % of Quantum Efficiency (QE) is routinely achieved when Cs<sub>2</sub>Te is formed.
- About 1 % of QE is usually realized through the RF gun operation.
- Good vacuum quality, less oxygen condition, is a key to realize and keep a higher QE.

Thank you for your attention!